

Search Notes

Application/Control No.

10/026,429

Examiner

CHAN S. PARK

Applicant(s)/Patent under
Reexamination

OKAJIMA, AIKO

Art Unit

2622

SEARCHED

Class	Subclass	Date	Examiner
399	81-83	9/8/2005	CP
358	1.15,1.12	9/8/2005	CP
358	498	9/8/2005	CP

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East (see the search history)	9/8/2005	CP